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## TYPES SN54LS630, SN54LS631, SN74LS630, SN74LS631 16-BIT PARALLEL ERROR DETECTION AND CORRECTION CIRCUITS

D2550, MARCH 1980

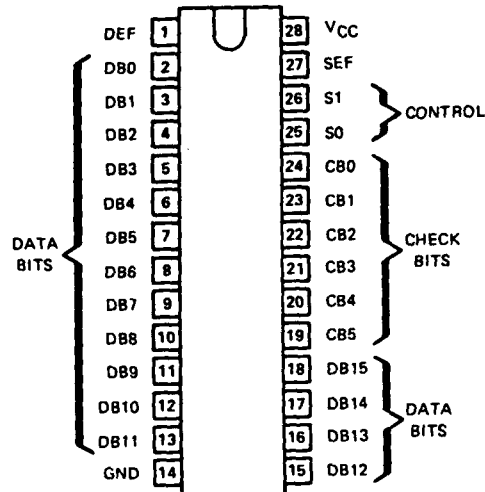
(TIM99630, TIM99631)

- Detects and Corrects Single-Bit Errors
- Detects and Flags Dual-Bit Errors
- Fast Processing Times:
  - Write Cycle: Generates Check Word in 45 ns Typical
  - Read Cycle: Flags Errors in 27 ns Typical
- Power Dissipation 600 mW Typical
- Choice of Output Configurations:
  - 'LS630 ... 3-State
  - 'LS631 ... Open-Collector

SN54LS' ... J PACKAGE

SN74LS' ... N PACKAGE

(TOP VIEW)



### Description

The 'LS630 and 'LS631 devices are 16-bit parallel error detection and correction circuits (EDACs) in 28-pin, 600-mil packages. They use a modified Hamming code to generate a 6-bit check word from a 16-bit data word. This check word is stored along with the data word during the memory write cycle. During the memory read cycle, the 22-bit words from memory are processed by the EDACs to determine if errors have occurred in memory.

Single-bit errors in the 16-bit data word are flagged and corrected.

Single-bit errors in the 6-bit check word are flagged, and the CPU sends the EDAC through the correction cycle even though the 16-bit word is not in error. The correction cycle will simply pass along the original 16-bit word in this case and produce error syndrome bits to pinpoint the error-generating location.

Dual-bit errors are flagged but not corrected. These dual errors may occur in any two bits of the 22-bit word from memory (two errors in the 16-bit data word, two errors in the 6-bit check word, or one error in each word).

The gross-error condition of all lows or all highs from memory will be detected. Otherwise, errors in three or more bits of the 22-bit word are beyond the capabilities of these devices to detect.

CONTROL FUNCTION TABLE

Memory Cycle	Control		EDAC Function	Data I/O	Check Word I/O	Error Flags	
	S1	S0				SEF	DEF
WRITE	L	L	Generate Check Word	Input Data	Output Check Word	L	L
READ	L	H	Read Data & Check Word	Input Data	Input Check Word	L	L
READ	H	H	Latch & Flag Errors	Latch Data	Latch Check Word	Enabled	
READ	H	L	Correct Data Word & Generate Syndrome Bits	Output Corrected Data	Output Syndrome Bits	Enabled	

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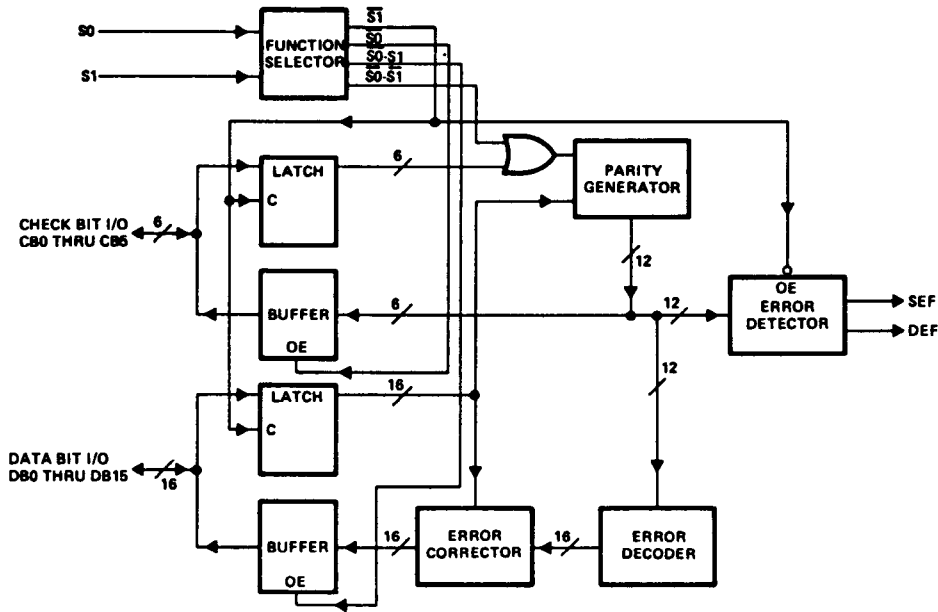
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7-465

# TYPES SN54LS630, SN54LS631, SN74LS630, SN74LS631

## 16-BIT PARALLEL ERROR DETECTION AND CORRECTION CIRCUITS

functional block diagram



ERROR FUNCTION TABLE

Total Number of Errors		Error Flags		Data Correction
16-Bit Data	6-Bit Checkword	SEF	DEF	
0	0	L	L	Not Applicable
1	0	H	L	Correction
0	1	H	L	Correction
1	1	H	H	Interrupt
2	0	H	H	Interrupt
0	2	H	H	Interrupt

In order to be able to determine whether the data from the memory is acceptable to use as presented to the bus, the EDAC must be strobed to enable the error flags and the flags will have to be tested for the zero condition.

The first case in the error function table represents the normal, no-error condition. The CPU sees lows on both flags. The next two cases of single-bit errors require data correction. Although the EDAC can discern the single check bit error and ignore it, the error flags are identical to the single error in the 16-bit data word. The CPU will ask for data correction in both cases. An interrupt condition to the CPU results in each of the last three cases, where dual errors occur.

### error detection and correction details

During a memory write cycle, six check bits (CB0-CB5) are generated by eight-input parity generators using the data bits as defined below. During a memory read cycle, the 6-bit check word is retrieved along with the actual data.

### 16-BIT PA

CHECKWORD BIT
CB0
CB1
CB2
CB3
CB4
CB5

The six check bits are:

Error detection is accomplished by parity generators/checkers. If an error has occurred and both SEF and DEF are set high, error and CB1, is inverted to ensure

If the parity of one or more data bits is set high. Any single error in the 6-bit checkword will be set high while the dual error

Any two-bit error will change the parity. A parity tree can only identify

Three or more simultaneous errors. A detectable error has occurred at

Error correction is accomplished by comparing the 12-bit parity signal (check word error) or three (

As the corrected word is made available, the error code. This syndrome co

### ERROR LOC

- DB0
- DB1
- DB2
- DB3
- DB4
- DB5
- DB6
- DB7
- DB8
- DB9
- DB10
- DB11
- DB12
- DB13
- DB14
- DB15
- CB0
- CB1
- CB2
- CB3
- CB4
- CB5
- NO ERROR

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CHECKWORD BIT	16-BIT DATA WORD															
	0	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15
CB0	x	x		x	x				x	x	x				x	
CB1	x		x	x		x	x		x			x				x
CB2		x	x		x	x		x			x		x			x
CB3	x	x	x				x	x			x	x	x			
CB4				x	x	x	x	x						x	x	x
CB5									x	x	x	x	x	x	x	x

The six check bits are parity bits derived from the matrix of data bits as indicated by "x" for each bit.

Error detection is accomplished as the 6-bit check word and the 16-bit data word from memory are applied to internal parity generators/checkers. If the parity of all six groupings of data and check bits are correct, it is assumed that no error has occurred and both error flags will be low. (It should be noted that the sense of two of the check bits, bits CB0 and CB1, is inverted to ensure that the gross-error condition of all lows and all highs is detected.)

If the parity of one or more of the check groups is incorrect, an error has occurred and the proper error flag or flags will be set high. Any single error in the 16-bit data word will change the sense of exactly three bits of the 6-bit check word. Any single error in the 6-bit check word changes the sense of only that one bit. In either case, the single error flag will be set high while the dual error flag will remain low.

Any two-bit error will change the sense of an even number of check bits. The two-bit error is not correctable since the parity tree can only identify single-bit errors. Both error flags are set high when any two-bit error is detected.

Three or more simultaneous bit errors can fool the EDAC into believing that no error, a correctable error, or an uncorrectable error has occurred and produce erroneous results in all three cases.

Error correction is accomplished by identifying the bad bit and inverting it. Identification of the erroneous bit is achieved by comparing the 16-bit data word and 6-bit check word from memory with the new check word with one (check word error) or three (data word error) inverted bits.

As the corrected word is made available on the data word I/O port, the check word I/O port presents a 6-bit syndrome error code. This syndrome code can be used to identify the bad memory chip.

ERROR SYNDROME TABLE

ERROR LOCATION	SYNDROME ERROR CODE					
	CB0	CB1	CB2	CB3	CB4	CB5
DB0	L	L	H	H	H	H
DB3	H	L	L	L	H	H
DB4	L	H	L	H	L	H
DB5	H	L	L	H	L	H
DB6	H	L	L	H	L	H
DB7	H	H	L	L	L	H
DB8	L	L	H	H	H	L
DB9	L	H	L	H	H	L
DB10	L	H	H	L	H	L
DB11	H	L	H	L	H	L
DB12	H	H	L	L	H	L
DB13	L	H	H	H	L	L
DB14	H	L	H	H	L	L
DB15	H	H	L	H	L	L
CB0	L	H	H	H	H	H
CB1	H	L	H	H	H	H
CB2	H	H	L	H	H	H
CB3	H	H	H	L	H	H
CB4	H	H	H	H	L	H
CB5	H	H	H	H	H	L
NO ERROR	H	H	H	H	H	H

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